
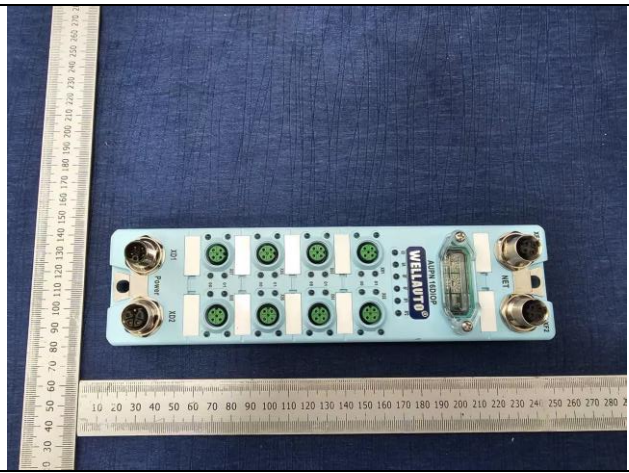




Prüfbericht-Nr.: Test Report No.:	CN25CAJF 001	Auftrags-Nr.: Order No.:	168530402	Seite 1 von 18 Page 1 of 18
Kunden-Referenz-Nr.: Client Reference No.:		Auftragsdatum: Order date.:	2025-01-07	
Auftraggeber: Client:	Shenzhen Wellauto Technology Co., Ltd. The Room 402, 405, BuildingC, Fenda High-tech Park, Xixiang, Hangcheng Street, Bao'an District, Shenzhen City, Guangdong, China			
Prüfgegenstand: Test item:	IP67 Series IO Module			
Bezeichnung / Typ-Nr.: Identification / Type No.:	See clause 5 on page 2 (Trademark:  华茂欧特)			
Auftrags-Inhalt: Order content:	TUV Rheinland - EMC service			
Prüfgrundlage: Test specification:	EN 55032:2015+A11+A1 EN 55035:2017+A11			
Wareneingangsdatum: Date of receipt:	2025-01-07			
Prüfmuster-Nr.: Test sample No.:	A003386883-001-002			
Prüfzeitraum: Testing period:	2025-01-07-2025-02-27			
Ort der Prüfung: Place of testing:	TÜV Rheinland (Shenzhen) Co., Ltd.			
Prüflaboratorium: Testing laboratory:	TÜV Rheinland (Shenzhen) Co., Ltd.			
Prüfergebnis*: Test result*:	Pass			
geprüft von: tested by: Chunli Zheng		genehmigt von: authorized by: Ware Xin		
Datum: Date: 2025-02-28		Ausstellungsdatum: Issue date: 2025-02-28		
Stellung / Position:	Sachverständige(r)/Expert	Stellung / Position:	Sachverständige(r)/Expert	
Sonstiges / Other:				
Zustand des Prüfgegenstandes bei Anlieferung: Condition of the test item at delivery:		Prüfmuster vollständig und unbeschädigt Test item complete and undamaged		
* Legende:	P(ass) = entspricht o.g. Prüfgrundlage(n)	F(ail) = entspricht nicht o.g. Prüfgrundlage(n)	N/A = nicht anwendbar	N/T = nicht getestet
Legend:	P(ass) = passed a.m. test specifications(s)	F(ail) = failed a.m. test specifications(s)	N/A = not applicable	N/T = not tested
Dieser Prüfbericht bezieht sich nur auf das o.g. Prüfmuster und darf ohne Genehmigung der Prüfstelle nicht auszugsweise vervielfältigt werden. Dieser Bericht berechtigt nicht zur Verwendung eines Prüfzeichens. <i>This test report only relates to the a. m. test sample. Without permission of the test center this test report is not permitted to be duplicated in extracts. This test report does not entitle to carry any test mark.</i>				

Remarks Anmerkungen

- | | |
|----------|---|
| 1 | <p>The equipment used during the specified testing period was calibrated according to our test laboratory calibration program. The equipment fulfils the requirements included in the relevant standards. The traceability of the test equipment used is ensured by compliance with the regulations of our management system.</p> <p>Detailed information regarding test conditions, equipment and measurement uncertainty is available in the test laboratory and could be provided on request.</p> <p><i>Alle eingesetzten Prüfmittel waren zum angegebenen Prüfzeitraum gemäß eines festgelegten Kalibrierungsprogramms unseres Prüfhauses kalibriert. Sie entsprechen den in den Prüfprogrammen hinterlegten Anforderungen. Die Rückverfolgbarkeit der eingesetzten Prüfmittel ist durch die Einhaltung der Regelungen unseres Managementsystems gegeben. Detaillierte Informationen bezüglich Prüfkonditionen, Prüfequipment und Messunsicherheiten sind im Prüflabor vorhanden und können auf Wunsch bereitgestellt werden.</i></p> |
| 2 | <p>As contractually agreed, this document has been signed digitally only. TÜV Rheinland has not verified and unable to verify which legal or other pertaining requirements are applicable for this document. Such verification is within the responsibility of the user of this document. Upon request by its client, TÜV Rheinland can confirm the validity of the digital signature by a separate document. Such request shall be addressed to our Sales department. An environmental fee for such additional service will be charged.</p> <p><i>Wie vertraglich vereinbart, wurde dieses Dokument nur digital unterzeichnet. Der TÜV Rheinland hat nicht überprüft, welche rechtlichen oder sonstigen diesbezüglichen Anforderungen für dieses Dokument gelten. Diese Überprüfung liegt in der Verantwortung des Benutzers dieses Dokuments. Auf Verlangen des Kunden kann der TÜV Rheinland die Gültigkeit der digitalen Signatur durch ein gesondertes Dokument bestätigen. Diese Anfrage ist an unseren Vertrieb zu richten. Eine Umweltgebühr für einen solchen zusätzlichen Service wird erhoben.</i></p> |
| 3 | <p>Test clauses with remark of * are subcontracted to qualified subcontractors and described under the respective test clause in the report. Deviations of testing specification(s) or customer requirements are listed in specific test clause in the report.</p> <p><i>Prüfklausel mit der Note * wurden an qualifizierte Unterauftragnehmer vergeben und sind unter der jeweiligen Prüfklausel des Berichts beschrieben. Abweichungen von Prüfspezifikation(en) oder Kundenanforderungen sind in der jeweiligen Prüfklausel im Bericht aufgeführt.</i></p> |
| 4 | <p>The decision rule for statements of conformity, based on numerical measurement results, in this test report is based on the "Zero Guard Band Rule" and "Simple Acceptance" in accordance with ILAC G8:2019 and IEC Guide 115:2021, unless otherwise specified in the applied standard mentioned on Page 1 of this report or requested by the customer. This means that measurement uncertainty is not taken in account and hence also not declared in the test report. For additional information to the resulting risk based of this decision rule please refer to ILAC G8:2019.</p> <p><i>Die Entscheidungsregel für Konformitätserklärungen basierend auf numerischen Messergebnissen in diesem Prüfbericht basiert auf der "Null-Grenzwert-Regel" und der "Einfachen Akzeptanz" gemäß ILAC G8:2019 und IEC Guide 115:2021, es sei denn, in der auf Seite 1 dieses Berichts genannten angewandten Norm ist etwas anderes festgelegt oder vom Kunden gewünscht. Dies bedeutet, dass die Messunsicherheit nicht berücksichtigt wird und daher auch nicht im Prüfbericht angegeben wird. Zu weiteren Informationen bezueglich des Risikos durch diese Entscheidungsregel siehe ILAC G8:2019.</i></p> |
| 5 | <p>AUPN 12DIP-BUS, AUPN 12DIN-BUS, AUPN 16DION, AUPN 16DIOP-E, AUPN 16DION-E, AUEC 12DIP-BUS, AUEC 12DIN-BUS, AUEC 16DIOP, AUEC 16DION, AUEC 16DIOP-E, AUEC 16DION-E, AUEC 14DIOP-A2, AUCB 12DIOP-BUS, AUCB 12DION-BUS, AUEI 12DIOP-BUS, AUEI 12DION-BUS, AUCP 12DIOP-BUS, AUCP 12DION-BUS, AUDP 12DIOP-BUS, AUPN</p> |

12DIP-BUS-W, AUPN 12DIN-BUS-W, AUPN 16DIOP-W, AUPN 16DION-W, AUEC 12DIP-BUS-W, AUEC 12DIN-BUS-W, AUEC 16DIOP-W, AUEC 16DION-W, AUEC 14DIOP-A2-W, AUCB 12DIOP-BUS-W, AUCB 12DION-BUS-W, AUEI 12DIOP-BUS-W, AUEI 12DION-BUS-W, AUCP 12DIOP-BUS-W, AUCP 12DION-BUS-W, AUDP 12DIOP-BUS-W, AUPN 16DIOP-78, AUPN 16DION-78, AUPN DBEP-A1-78, AUEC 16DIOP-78, AUEC 16DION-78, AUPN 16DIOP

TEST SUMMARY

5.1.1 RADIATED EMISSIONS (BELOW 1GHz)

RESULT: Pass

5.1.2 RADIATED EMISSIONS (ABOVE 1GHz)

Not Applicable

6.2.1 CONTINUOUS RF ELECTROMAGNETIC FIELD DISTURBANCES, SWEPT TEST

RESULT: Pass

6.2.2 CONTINUOUS RF ELECTROMAGNETIC FIELD DISTURBANCES, SPOT TEST

RESULT: Pass

6.3.1 ELECTROSTATIC DISCHARGES (ESD)

RESULT: Pass

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1. General Remarks

1.1 Complementary Materials

All attachments are integral parts of this test report. This applies especially to the following appendix:

Appendix 1: Test result

Appendix 2: Measurement uncertainties

2. Test Sites

2.1 Test Facilities

TÜV Rheinland (Shenzhen) Co., Ltd.

2-3F, 101 & 102, No.2 Nuclear Power Industrial Park Fuming Community, Fucheng Street,
Longhua District Shenzhen, Guangdong Province P.R. China

CNAS Registration No.: L3080

2.2 List of Test and Measurement Instruments

Table 1: List of Test and Measurement Equipment

TÜV Rheinland (Shenzhen) Co., Ltd.

Radiated Emission (3m chamber)				
Equipment	Manufacturer	Model No.	Serial No.	Cal. Until
3m SAC	ETS-Lindgren	SAC3	CT001632-Q1362	2027-09-11
EMI Test Receiver	R&S	ESR7	102111	2025-08-18
Trilog-Broadband antenna	SCHWARZBECK	VULB9168	0945	2025-07-17
EMC32 test software	R&S	EMC32(Ver.10.50.00)	N/A	N/A
Radio Frequency Electromagnetic Fields (RS)				
Equipment	Manufacturer	Model No.	Serial No.	Cal. Until
3m FAC	ETS	FAC3	CT001632-Q1360	2027-09-12
Signal Generator	R&S	SMB100A	115183	2025-08-18
Power Amplifier	R&S	BBA150-BC250	103102	2025-08-18
Power Amplifier	R&S	BBA150-D110E100	103117	2025-08-18
NRP6AN Average Power Sensor	R&S	NRP6AN	101161	2025-10-11
NRP6AN Average power sensor	R&S	NRP6AN	101162	2025-10-11
Stacked double Log.-Per. Antenna1825022	SCHWARZBECK	STLP 9128E	0153	2026-01-11
Stacked Log.-Per. Antenna	SCHWARZBECK	STLP 9149	00520	2026-01-11
EMC32 Test Software	R&S	EMC32(Ver.10.30.01)	N/A	N/A
Electrostatic Discharge (ESD)				
Equipment	Manufacturer	Model No.	Serial No.	Cal. Until
ESD Tester	TESEQ	NSG-437	1282	2025-08-02

3. General Product Information

3.1 Product Function and Intended Use

The EUT is a IP67 Series IO Module used for industrial environments.

According to the client's declaration, the above models AUPN 12DIP-BUS, AUPN 12DIN-BUS, AUPN 16DION, AUPN 16DIOP-E, AUPN 16DION-E, AUEC 12DIP-BUS, AUEC 12DIN-BUS, AUEC 16DIOP, AUEC 16DION, AUEC 16DIOP-E, AUEC 16DION-E, AUEC 14DIOP-A2, AUCB 12DIOP-BUS, AUCB 12DION-BUS, AUEI 12DIOP-BUS, AUEI 12DION-BUS, AUCP 12DIOP-BUS, AUCP 12DION-BUS, AUDP 12DIOP-BUS, AUPN 12DIP-BUS-W, AUPN 12DIN-BUS-W, AUPN 16DIOP-W, AUPN 16DION-W, AUEC 12DIP-BUS-W, AUEC 12DIN-BUS-W, AUEC 16DIOP-W, AUEC 16DION-W, AUEC 14DIOP-A2-W, AUCB 12DIOP-BUS-W, AUCB 12DION-BUS-W, AUEI 12DIOP-BUS-W, AUEI 12DION-BUS-W, AUCP 12DIOP-BUS-W, AUCP 12DION-BUS-W, AUDP 12DIOP-BUS-W, AUPN 16DIOP-78, AUPN 16DION-78, AUPN DBEP-A1-78, AUEC 16DIOP-78, AUEC 16DION-78 are the same as the original ones AUPN 16DIOP in circuit design, layout only difference them Software version target different sales markets.

For more information refer to the Instruction Manual.

3.2 Ratings and System Details

Operating Voltage : DC 24V

Testing voltage: DC 24V

Protection class: III

*Highest internal frequency: Fx < 108MHz

3.3 Independent Operation Modes

The basic operation modes are:

- A. On
- B. Off

3.4 Noise Generating and Noise Suppressing Parts

N/A

3.5 Submitted Documents

- Rating Label

- Instruction Manual

4. Test Set-up and Operation Modes

4.1 Principle of Configuration Selection

Emission: The equipment under test (EUT) was configured to measure its highest possible radiation level. The test modes were adapted accordingly in reference to the instructions for use.

Immunity: The equipment under test (EUT) was configured to have its highest possible susceptibility against the tested phenomena. The test modes were adapted accordingly in reference to the instructions for use.

4.2 Test Operation and Test Software

Test operation refers to test setup in section 5 & 6. Pre-test in all operation modes, and find out the worst case for compliance test.

According to clause 3.1, all tests were performed on model AUPN 16DIOP in this report.

4.3 Special Accessories and Auxiliary Equipment

N/A

4.4 Countermeasures to achieve EMC Compliance

The test sample, which has been tested, contained the noise suppression parts as described in the Constructional Data Form or the Technical Construction File. No additional measures were employed to achieve compliance.

5. Test Results EMISSION

5.1 Emission in the Frequency Range above 30 MHz

5.1.1 Radiated Emissions (Below 1GHz)

RESULT:**Pass**

Date of testing	:	2025-02-27
Test standard	:	EN 55032:2015+A11+A1
Frequency range	:	30 - 1000MHz *
Classification	:	Class A
Limits	:	Table A.2 of EN 55032:2015+A11+A1
Kind of test site	:	3m Semi-Anechoic Chamber
Tested Port	:	Enclosure

Test setup

Input Voltage	:	DC 24V
Operation Condition	:	According to clause 7.3 of CISPR 16-2-3:2016 & Annex D of EN 55032:2015+A11+A1
Operation mode	:	A
Earthing	:	Not connected
Ambient temperature	:	Refer to Appendix 1
Relative humidity	:	Refer to Appendix 1
Atmospheric pressure	:	Refer to Appendix 1

Detailed test data refer to attached Appendix 1.

* Remark: The highest internal source of an EUT is defined as the highest frequency generated or used within the EUT or on which the EUT operates or tunes, details refer to section 3.2.

- ☒ Highest frequency is less than 108MHz, measurement shall only be made up to 1GHz
- ☐ Highest frequency is between 108 & 500MHz, measurement shall only be made up to 2GHz
- ☐ Highest frequency is between 500 & 1GHz, measurement shall only be made up to 5GHz
- ☐ Highest frequency is above 1GHz, measurement shall be made up to 5 times the highest frequency or 6GHz, whichever is less

Method: Measurements were made in a 3-meter semi-anechoic chamber or Open Area Test Site that complies to CISPR 16. Preliminary (peak) measurements were performed at an antenna to EUT separation distance of 3 meter below 1GHz and 3 meter above 1GHz. The EUT was rotated 360° about its azimuth with the receive antenna located at various heights in horizontal and vertical polarities. Final measurements (quasi-peak detector below 1GHz) were then performed by rotating the EUT 360° and adjusting the receive antenna height from 1 to 4 m. All frequencies were investigated in both horizontal and vertical antenna polarity, where applicable.

5.1.2 Radiated Emissions (Above 1GHz)

Not Applicable

Date of testing	:	--
Test standard	:	EN 55032:2015+A11+A1
Frequency range	:	1 – 6GHz*
Classification	:	Class A
Limits	:	Table A.3 of EN 55032:2015+A11+A1
Kind of test site	:	3m Semi-Anechoic Chamber with RF absorber on the RGP
Tested Port	:	Enclosure

* Remark: The highest internal source of an EUT is defined as the highest frequency generated or used within the EUT or on which the EUT operates or tunes, details refer to section 3.2.

- ☒ Highest frequency is less than 108MHz, measurement shall only be made up to 1GHz
- ☐ Highest frequency is between 108 & 500MHz, measurement shall only be made up to 2GHz
- ☐ Highest frequency is between 500 & 1GHz, measurement shall only be made up to 5GHz
- ☐ Highest frequency is above 1GHz, measurement shall be made up to 5 times the highest frequency or 6GHz, whichever is less

Method: Measurements were made in a 3-meter semi-anechoic chamber or Open Area Test Site that complies to CISPR 16. Preliminary (peak) measurements were performed at an antenna to EUT separation distance of 3 meter below 1GHz and 3 meter above 1GHz. The EUT was rotated 360° about its azimuth with the receive antenna located at various heights in horizontal and vertical polarities. Final measurements (quasi-peak detector below 1GHz) were then performed by rotating the EUT 360° and adjusting the receive antenna height from 1 to 4 m. All frequencies were investigated in both horizontal and vertical antenna polarity, where applicable.

6. Test Results IMMUNITY

6.1 Classification of apparatus

According to EN 55035:2017+A11, the EUT shall be tested in accordance with clause 4 & 5, and comply with the performance criterion in table 1 of clause 5.

Continuous Disturbance

Continuous RF electromagnetic field disturbances swept test, spot test	Criterion A
Power Frequency Magnetic Fields *	Criterion A

Transient Disturbance

Electrostatic Discharges (ESD)	Criterion B
--------------------------------	--------------------

Remark:

*The EUT do not contain devices susceptible to magnetic fields, therefore the Power-Frequency Magnetic Fields test is not necessary.

6.2 Continuous Disturbances

6.2.1 Continuous RF electromagnetic field disturbances, swept test

RESULT: Pass

Date of Testing : 2025-02-27
Test Specification : EN 55035:2017+A11
Basic Standard : IEC 61000-4-3:2006+A1+A2
Criterion : A
Frequency Range : 80 - 1000MHz
Test Level : 3V/m (Unmodulated, r.m.s.)
Modulation : AM 80%, 1kHz sine-wave
Tested port : Enclosure

Test setup

Input Voltage : DC 24V
Operation Mode : A
Earthing : Not connected
Ambient temperature : 23.2°C
Relative humidity : 43.2%
Atmospheric pressure : 101kPa

Test Result

Frequency Range	Polarization	Test Level (Unmodulated, rms)	Performance Criterion	Location	Result
80MHz to 1000MHz	Horizontal and Vertical	3V/m (rms)	A	Front/Rear/Left /Right	Pass
Remark: Operating as intended, no degradation detected during and after testing.					

6.2.2 Continuous RF electromagnetic field disturbances, spot test**RESULT:****Pass**

Date of Testing : 2025-02-27
Test Specification : EN 55035:2017+A11
Basic Standard : IEC 61000-4-3:2006+A1+A2
Criterion : A
Frequency Range : 1800MHz, 2600MHz, 3500MHz, 5000MHz
Test Level : 3V/m (Unmodulated, r.m.s.)
Modulation : AM 80%, 1kHz sine-wave
Tested port : Enclosure

Test setup

Input Voltage : DC 24V
Operation Mode : A
Earthing : Not connected
Ambient temperature : 23.2°C
Relative humidity : 43.2%
Atmospheric pressure : 101kPa

Test Result

Frequency	Polarization	Test Level (Unmodulated, rms)	Performance Criterion	Location	Result
1800MHz, 2600MHz, 3500MHz, 5000MHz	Horizontal and Vertical	3V/m (rms)	A	Front/Rear/Left /Right	Pass

Remark: Operating as intended, no degradation detected during and after testing.

6.3 Transient Disturbances

6.3.1 Electrostatic Discharges (ESD)

RESULT:**Pass**

Date of testing : 2025-02-27
Test Specification : EN 55035:2017+A11
Basic Standard : IEC 61000-4-2:2008
Criterion : B
Charge voltage : $\pm 2\text{kV}$, $\pm 4\text{kV}$, $\pm 8\text{kV}$ (air discharge)
 $\pm 4\text{kV}$ (contact discharge)
Number of discharges : >10

Test Setup

Input Voltage : DC 24V
Operation Mode : A
Earthing : Not connected
Ambient temperature : 23.0°C
Relative humidity : 43.8%
Atmospheric pressure : 101kPa

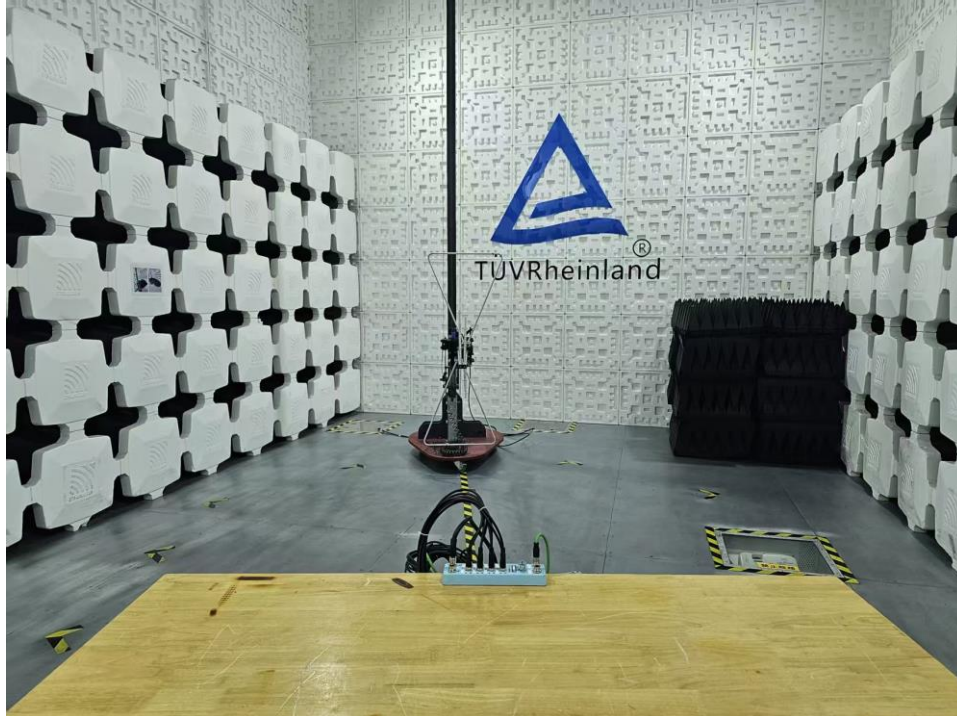
Test Result

Test Point	Test Mode	Test Level (kV)	Performance Criterion	Description	Result
VCP	C	± 4.0	B	No failure detected	Pass
HCP	C	± 4.0	B	No failure detected	Pass
Shell	A	± 2.0 , ± 4.0 , ± 8.0	B	No failure detected	Pass

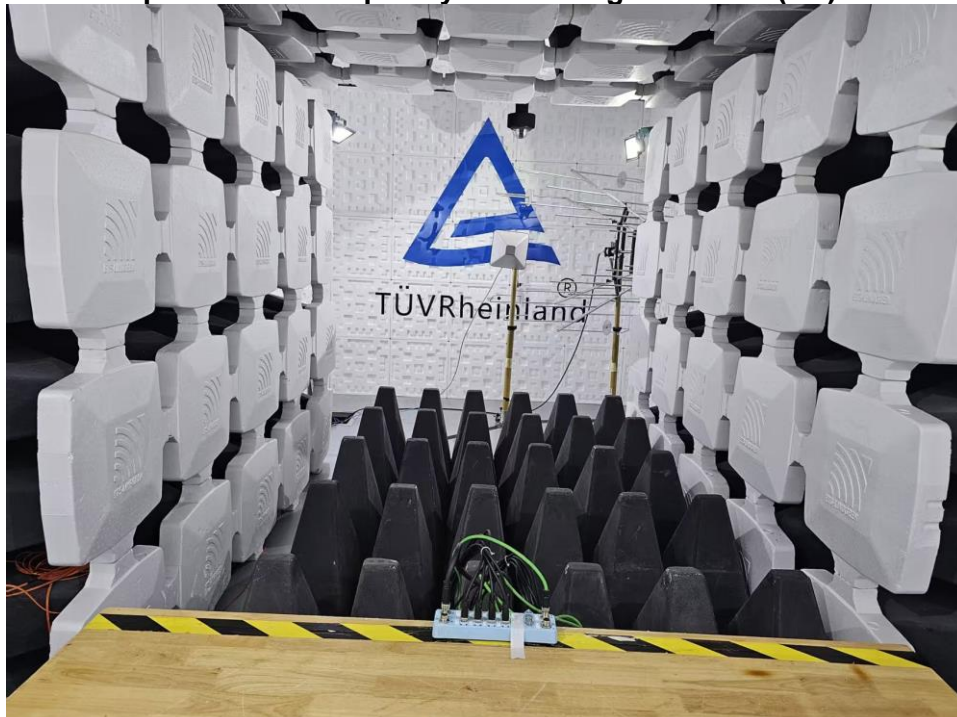
Note: A-Air discharge; C- Contact Discharge; VCP- Vertical Coupling Plane; HCP- Horizontal Coupling Plane

7. Photographs of the Test Set-Up

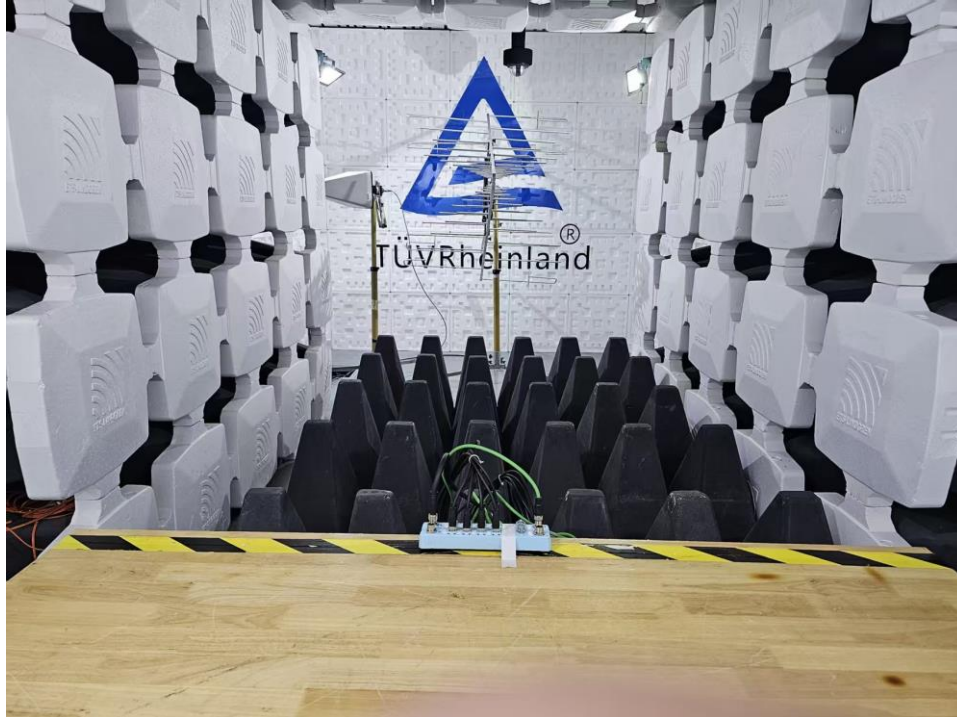
Photograph 1: Set-up for Radiated Emission (30-1000MHz)



Photograph 2: Set-up for Radio-Frequency Electromagnetic Field (RS) Below 1GHz



Photograph 3: Set-up for Radio-Frequency Electromagnetic Field (RS) Above 1GHz



Photograph 4: Set-up for Electrostatic Discharges (ESD)



8. List of Tables

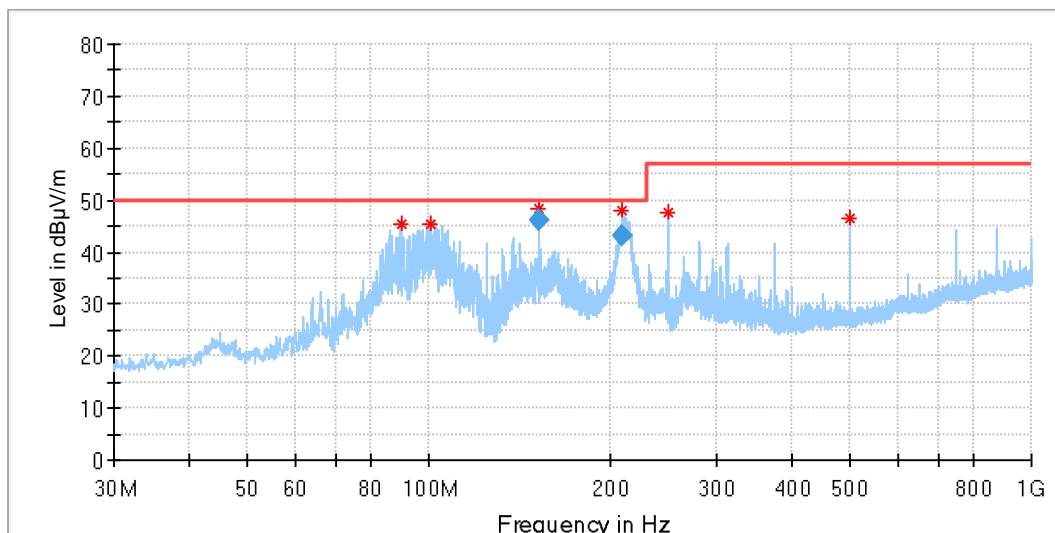
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Photograph 3: Set-up for Radio-Frequency Electromagnetic Field (RS) Above 1GHz.....	17
Photograph 4: Set-up for Electrostatic Discharges (ESD)	17

Appendix 1: Test Results of Radiated Emission

EUT Name: IP67 Series IO Module
Order Number: 168530402
Model: AUPN 16DIOP
Test Mode: ON operation
Test Voltage: DC24V
Test Standard: EN 55032
Test By:/Review By: Steve Lan/Shower Dai
Tem./Hum./Pressure: 21.9°C/49.8%/101kPa
Remark: 3m chamber



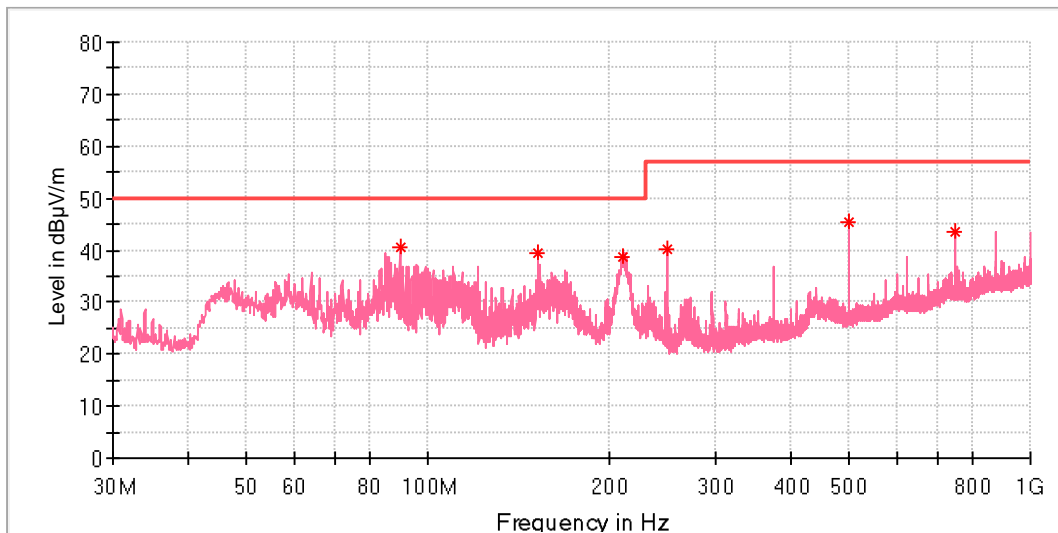
Critical Freqs

Frequency (MHz)	MaxPeak (dBμV/m)	Limit (dBμV/m)	Margin (dB)	Height (cm)	Pol	Azimuth (deg)	Corr. (dB/m)
89.87	45.52	50.00	4.48	200.0	H	182.00	15.12
100.92	45.43	50.00	4.57	200.0	H	182.00	16.35
152.33	48.27	50.00	1.73	200.0	H	238.00	21.02
209.78	47.99	50.00	2.01	200.0	H	311.00	17.82
249.97	47.80	57.00	9.20	100.0	H	46.00	19.91
499.97	46.65	57.00	10.35	100.0	H	85.00	26.80

Final Result

Frequency (MHz)	QuasiPeak (dBμV/m)	Limit (dBμV/m)	Margin (dB)	Meas. Time (ms)	Bandwidth (kHz)	Height (cm)	Pol	Azimuth h (deg)	Corr. (dB/m)
152.33	46.14	50.00	3.86	1000.00	120.00	200.0	H	238.00	21.03
209.78	43.33	50.00	6.67	1000.00	120.00	200.0	H	311.00	17.81

EUT Name:	IP67 Series IO Module
Order Number:	168530402
Model:	AUPN 16DIOP
Test Mode:	ON operation
Test Voltage:	DC24V
Test Standard:	EN 55032
Test By:/Review By:	Steve Lan/Shower Dai
Tem./Hum./Pressure:	21.9°C/49.8%/101kPa
Remark:	3m chamber



Critical_Freqs

Frequency (MHz)	MaxPeak (dBμV/m)	Limit (dBμV/m)	Margin (dB)	Height (cm)	Pol	Azimuth (deg)	Corr. (dB/m)
89.82	40.55	50.00	9.45	100.0	V	203.00	15.13
152.38	39.31	50.00	10.69	100.0	V	305.00	21.03
209.99	38.82	50.00	11.18	100.0	V	252.00	17.81
249.97	40.04	57.00	16.96	100.0	V	265.00	19.91
499.97	45.38	57.00	11.62	100.0	V	44.00	26.80
750.01	43.63	57.00	13.37	100.0	V	35.00	31.97

Final Result

Frequency (MHz)	QuasiPeak (dBμV/m)	Limit (dBμV/m)	Margin (dB)	Meas. Time (ms)	Bandwidth (kHz)	Height (cm)	Pol	Azimuth h (deg)	Corr. (dB/m)
---	---	---	---	---	---	---		---	---

Measurement Uncertainties

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the apparatus.

The reported expanded uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor of $k=2$, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Table 1: Measurement Uncertainty levels

Test	Parameters	Expanded uncertainty (U_{lab})	Expanded uncertainty (U_{cispr})
Radiated Emission (3m SAC)	Level accuracy (30MHz to 1000MHz)	± 4.52 dB	± 6.3 dB

As U_{lab} in all applicable tests listed above are less than U_{cispr} according to CISPR 16-4-2:2011,

- compliance is deemed to occur if no measured disturbance exceeds the disturbance limit;
- non-compliance is deemed to occur if any measured disturbance exceeds the disturbance limit.

END OF REPORT